

## **REMARKS**

In view of the above amendments and the following remarks, reconsideration of the rejection and further examination are requested.

Initially, it is noted that this amendment includes the substance of the arguments discussed in a Telephone Interview with the Examiner, conducted on August 8, 2009, distinguishing the present invention over the art cited in the double patenting rejection and the 102(b) rejection. As a result of the discussion, the Examiner agreed that the present invention is distinguishable over the references cited in the double patenting rejection, as well as the 102(b) rejection, but required a more explicit delineation between the two aging periods to be recited in the claims. The Examiner's primary concern was that in the first aging period, although the claims previously recited that the voltage is applied when the scan electrode voltage is higher than the sustain electrode voltage, they did not explicitly recite that the voltage is not applied when the sustain electrode voltage is higher than the scan electrode voltage. The Examiner had the same concern with the second aging period. As discussed in detail below, the claims have been amended to address the Examiner's concerns. In addition, the diagram discussed in the Examiner's Interview has been attached at the end, but is not to be entered as a drawing figure of the application.

### **Rejection under Non-Statutory Double Patenting:**

Claim 1 has been rejected on the grounds of the judicially created doctrine of double patenting over claim 1 of Yamauchi (US 7,338,337). This rejection is respectfully traversed and submitted to be inapplicable to the above claims for the following reasons.

Claim 1 recites a first aging period in which aging is carried out by applying voltages alternately and continuously to the scan electrodes and the sustain electrodes, and in which at least any one of the scan electrodes, the sustain electrodes, and the address electrodes undergo an application of voltage for suppressing a first self-erase discharge only when the scan electrodes carry a voltage level higher than the sustain electrodes, and a second aging period in which aging is carried

out by applying voltages alternately and continuously to the scan electrodes and the sustain electrodes, and in which at least any one of the scan electrodes, the sustain electrodes, and the address electrodes undergo an application of voltage for suppressing a second self-erase discharge only when the sustain electrodes carry a voltage level higher than the scan electrodes.

For example, Figure 4A shows that during the first aging period, when the scan electrodes carry a voltage level higher than the sustain electrodes, a voltage is applied to at least one of the electrodes recited in the claim to suppress a self-erase discharge that would normally follow an aging discharge. In contrast, Figure 4B shows that during the second aging period when the sustain electrodes carry a voltage level higher than the scan electrodes, a voltage is applied to at least one of the electrodes recited in the claim to suppress a self-erase discharge that would normally follow an aging discharge. Yamauchi fails to disclose the features of claim 1 discussed above.

Yamauchi discloses that a suppressing voltage is applied twice every period. Once at every peak of the AC wave (because at the peak, the scan voltage is higher) and once at every trough of an AC wave (because at the trough, the sustain voltage is higher) as depicted in Figures 5A (showing the scan voltage as higher), 5B (showing the sustain voltage as higher), and 5C (showing the suppressing voltage being applied twice every cycle corresponding to Figures 5A and 5B). This process is continued for the entire aging period. Thus, in Yamauchi there is only one aging period where the suppressing voltage is applied twice every cycle. However, there is not a first aging period and a second aging period where a suppressing voltage is applied differently in each period. Therefore, Yamauchi does not disclose or suggest a first aging period in which aging is carried out by applying voltages alternately and continuously to the scan electrodes and the sustain electrodes, and in which at least any one of the scan electrodes, the sustain electrodes, and the address electrodes undergo an application of voltage for suppressing a first self-erase discharge only when the scan electrodes carry a voltage level higher than the sustain electrodes, and a second aging period in which aging is carried out by applying voltages alternately and continuously to the scan electrodes and the sustain electrodes, and in which at least any one of the scan electrodes, the sustain electrodes, and the address electrodes undergo an

application of voltage for suppressing a second self-erase discharge only when the sustain electrodes carry a voltage level higher than the scan electrodes as recited in claim 1. Since it is apparent that the aging period in Yamaguchi is distinct and not obvious from the first and second aging periods of claim 1, withdrawal of the double patenting rejection is respectfully requested.

**Rejection under 35 U.S.C. §102(b):**

Claim 1 has been rejected under 35 U.S.C. §102(b) as being anticipated by Fujitsu (JP 09-251841 A). This rejection is respectfully traversed and submitted to be inapplicable to the above claims for the following reasons.

Claim 1 is not anticipated by Fujitsu for reasons similar to those discussed above with regard to the double-patenting rejection. Specifically, Fujitsu discloses a method of manufacturing a display panel using a single aging period. However, Fujitsu does not disclose a first aging period and a second aging period where a suppressing voltage is applied differently in each period. Therefore, Fujitsu does not disclose a first aging period in which aging is carried out by applying voltages alternately and continuously to the scan electrodes and the sustain electrodes, and in which at least any one of the scan electrodes, the sustain electrodes, and the address electrodes undergo an application of voltage for suppressing a first self-erase discharge only when the scan electrodes carry a voltage level higher than the sustain electrodes, and a second aging period in which aging is carried out by applying voltages alternately and continuously to the scan electrodes and the sustain electrodes, and in which at least any one of the scan electrodes, the sustain electrodes, and the address electrodes undergo an application of voltage for suppressing a second self-erase discharge only when the sustain electrodes carry a voltage level higher than the scan electrodes as recited in claim 1. As a result, claim 1 is not anticipated by Fujitsu.

**Rejection under 35 U.S.C. §103(a):**

Claim 2 has been rejected under 35 U.S.C. §103(a) as being unpatentable over Fujitsu (JP 09-251841 A) in view of Yoo (US 7,173,374). This rejection is respectfully traversed and

submitted to be inapplicable to the above claims for the following reasons.

Claim 2 is ultimately dependent on independent claim 1, which is discussed in detail above.

Yoo is relied upon in the rejection as disclosing a PDP apparatus where the scan and sustain electrodes have different sizes and, as a result, the period during which the voltage is applied to the scan electrode is shorter than the period during which the voltage is applied to the sustain electrode. However, it is apparent Yoo fails to disclose or suggest the features lacking from Fujitsu discussed above with regard to independent claim 1. Accordingly, no obvious combination of Fujitsu and Yoo would result in, or otherwise render obvious under 35 U.S.C. §103(a), the features recited in claims 1 and 2. Therefore, claims 1 and 2 are patentable over the combination of Fujitsu and Yoo.

Because of the above-mentioned distinctions, it is believed clear that claims 1-2 are allowable over the references relied upon in the rejections. Furthermore, it is submitted that the distinctions are such that a person having ordinary skill in the art at the time of the invention would not have been motivated to make any combination of the references of record in such a manner as to result in, or otherwise render obvious, the present invention as recited in 1-2. Therefore, it is submitted that claims 1-2 are clearly allowable over the prior art of record.

In view of the above amendments and remarks, it is submitted that the present application is now in condition for allowance. The examiner is invited to contact the undersigned by telephone if it is felt that there are issues remaining which must be resolved before allowance of the application.

Respectfully submitted,

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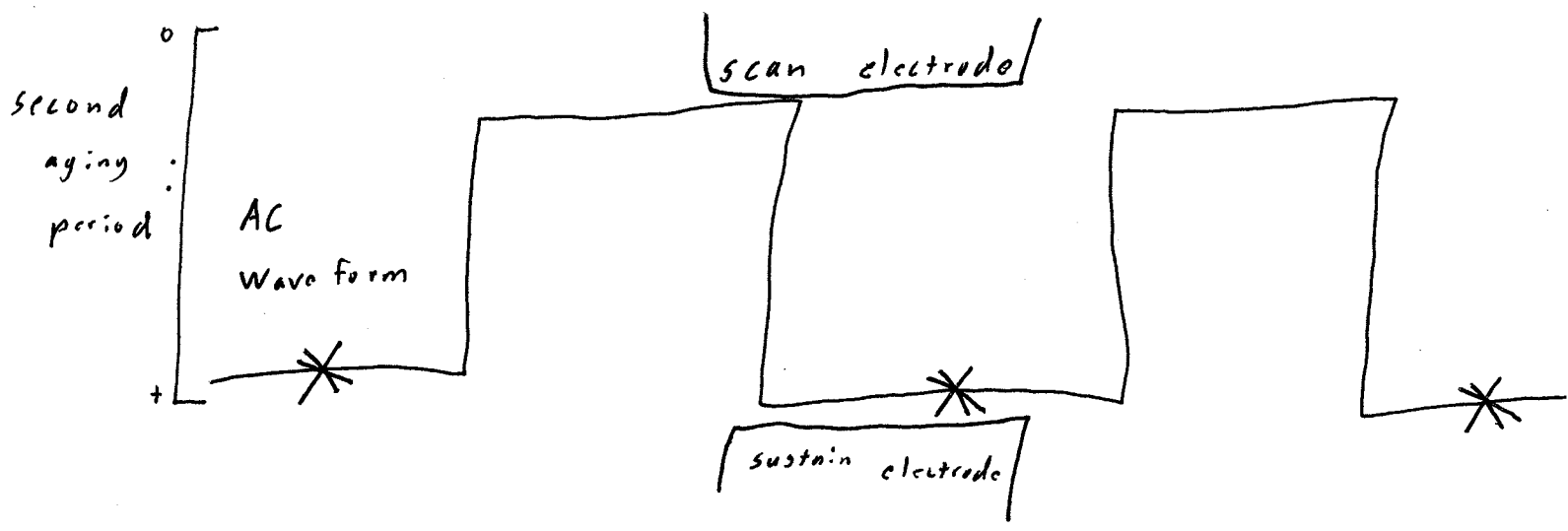
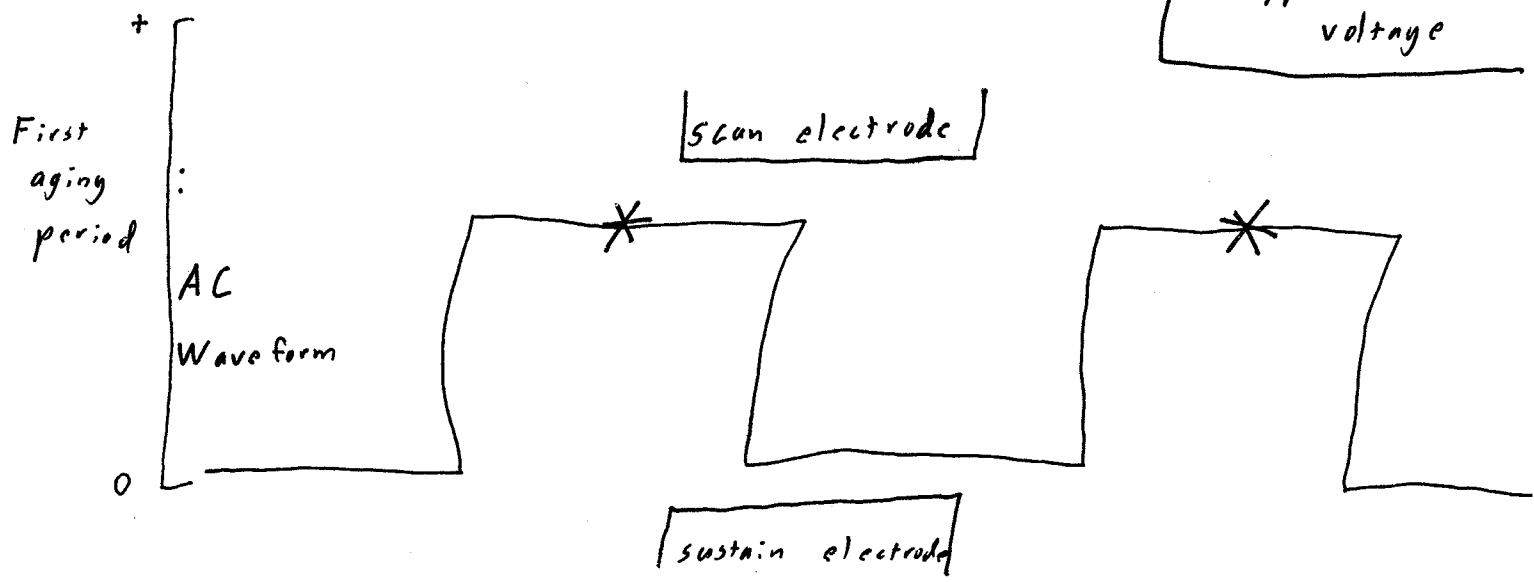
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Not to be entered.  
For reference only.

Present Invention:

\* represents  
an applied  
suppressing  
voltage



Yamaguchi:

